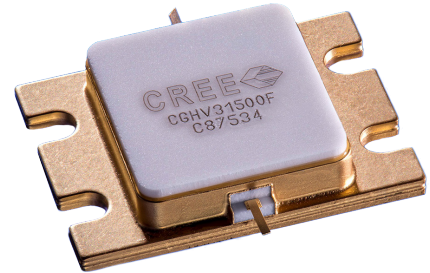


CGHV31500F

500 W, 2.7 - 3.1 GHz, 50-Ohm Input/Output Matched,
GaN HEMT for S-Band Radar Systems

Description

CGHV31500F is a gallium nitride (GaN) high electron mobility transistor (HEMT) designed specifically with high efficiency, high gain and wide bandwidth capabilities, which makes the CGHV31500F ideal for 2.7 - 3.1 GHz S-Band radar amplifier applications. The transistor is supplied in a ceramic/metal flange package, type 440226.



PN: CGHV31500F
Package Type: 440226

Typical Performance Over 2.7-3.1 GHz ($T_c = 25^\circ\text{C}$) of Demonstration Amplifier

Parameter	2.7 GHz	2.9 GHz	3.1 GHz	Units
Output Power	650	705	506	W
Gain	12.1	12.5	11.8	dB
Drain Efficiency	70	68	58	%

Note: Measured in the CGHV31500F-AMP application circuit, under 100 μs pulse width, 10% duty cycle, $P_{IN} = 46\text{ dBm}$

Features

- 2.7 - 3.1 GHz Operation
- 650 W Typical Output Power
- 12 dB Power Gain
- 65% Typical Drain Efficiency
- 50 Ohm Internally Matched
- <0.3 dB Pulsed Amplitude Droop



Absolute Maximum Ratings (not simultaneous)

Parameter	Symbol	Rating	Units	Conditions
Pulse Width	PW	500	μs	
Duty Cycle	DC	10	%	
Drain-Source Voltage	V _{DSS}	150	Volts	25 °C
Gate-to-Source Voltage	V _{GS}	-10, +2	Volts	25 °C
Storage Temperature	T _{STG}	-65, +150	°C	
Operating Junction Temperature	T _J	225	°C	
Maximum Forward Gate Current	I _{GMAX}	80	mA	25 °C
Maximum Drain Current ¹	I _{DMAX}	24	A	25 °C
Soldering Temperature ²	T _S	245	°C	
Screw Torque	τ	40	in-oz	
Pulsed Thermal Resistance, Junction to Case	R _{θJC}	0.22	°C/W	100 μsec, 10%, 85 °C, P _{DISS} = 376 W
Case Operating Temperature	T _C	-40, +125	°C	

Notes:

¹ Current limit for long term, reliable operation

² Refer to the Application Note on soldering at wolfspeed.com/rf/document-library

Electrical Characteristics

Characteristics	Symbol	Min.	Typ.	Max.	Units	Conditions
DC Characteristics¹ (T_C = 25 °C)						
Gate Threshold Voltage	V _{GS(th)}	-3.8	-3.0	-2.3	V _{DC}	V _{DS} = 10 V, I _D = 83.6 mA
Gate Quiescent Voltage	V _{GS(Q)}	–	-2.7	–	V _{DC}	V _{DS} = 50 V, I _D = 0.5 A
Saturated Drain Current ²	I _{DS}	62.7	75.5	–	A	V _{DS} = 6.0 V, V _{GS} = 2.0 V
Drain-Source Breakdown Voltage	V _{BR}	125	–	–	V _{DC}	V _{GS} = -8 V, I _D = 83.6 mA

Notes:

¹ Measured on wafer prior to packaging

² Scaled from PCM data



Electrical Characteristics Continued...

Characteristics	Symbol	Min.	Typ.	Max.	Units	Conditions
RF Characteristics³ ($T_c = 25^\circ\text{C}$, $F_0 = 2.7 - 3.1\text{ GHz}$ unless otherwise noted)						
Output Power at 2.7 GHz	P_{OUT1}	473	630	–	W	$V_{DD} = 50\text{ V}$, $I_{DQ} = 500\text{ mA}$, $P_{IN} = 46\text{ dBm}$
Output Power at 2.9 GHz	P_{OUT2}	555	725	–	W	$V_{DD} = 50\text{ V}$, $I_{DQ} = 500\text{ mA}$, $P_{IN} = 46\text{ dBm}$
Output Power at 3.1 GHz	P_{OUT3}	473	630	–	W	$V_{DD} = 50\text{ V}$, $I_{DQ} = 500\text{ mA}$, $P_{IN} = 46\text{ dBm}$
Gain at 2.7 GHz	G_{P1}	–	12.1	–	dB	$V_{DD} = 50\text{ V}$, $I_{DQ} = 500\text{ mA}$, $P_{IN} = 46\text{ dBm}$
Gain at 2.9 GHz	G_{P2}	–	12.5	–	dB	$V_{DD} = 50\text{ V}$, $I_{DQ} = 500\text{ mA}$, $P_{IN} = 46\text{ dBm}$
Gain at 3.1 GHz	G_{P3}	–	11.8	–	dB	$V_{DD} = 50\text{ V}$, $I_{DQ} = 500\text{ mA}$, $P_{IN} = 46\text{ dBm}$
Drain Efficiency at 2.7 GHz	D_{E1}	57	68	–	%	$V_{DD} = 50\text{ V}$, $I_{DQ} = 500\text{ mA}$, $P_{IN} = 46\text{ dBm}$
Drain Efficiency at 2.9 GHz	D_{E2}	54	67	–	%	$V_{DD} = 50\text{ V}$, $I_{DQ} = 500\text{ mA}$, $P_{IN} = 46\text{ dBm}$
Drain Efficiency at 3.1 GHz	D_{E3}	50	62	–	%	$V_{DD} = 50\text{ V}$, $I_{DQ} = 500\text{ mA}$, $P_{IN} = 46\text{ dBm}$
Small Signal Gain	S_{21}	11.25	14.5	–	dB	$V_{DD} = 50\text{ V}$, $I_{DQ} = 500\text{ mA}$, $P_{IN} = 10\text{ dBm}$
Input Return Loss	S_{11}	–	-15	-5.25	dB	$V_{DD} = 50\text{ V}$, $I_{DQ} = 500\text{ mA}$, $P_{IN} = 10\text{ dBm}$
Output Return Loss	S_{22}	–	-5	-3	dB	$V_{DD} = 50\text{ V}$, $I_{DQ} = 500\text{ mA}$, $P_{IN} = 10\text{ dBm}$
Amplitude Droop	D	–	-0.3	–	dB	$V_{DD} = 50\text{ V}$, $I_{DQ} = 500\text{ mA}$, $P_{IN} = 46\text{ dBm}$
Output Stress Match	VSWR	–	5:1	–	Ψ	No damage at all phase angles, $V_{DD} = 50\text{ V}$, $I_{DQ} = 500\text{ mA}$, $P_{IN} = 46\text{ dBm}$ Pulsed

Notes:

³ Measured in CGHV31500F-AMP. Pulse Width = 100 μs , Duty Cycle = 10%

Typical Performance

Figure 1. CGHV31500F S-Parameters

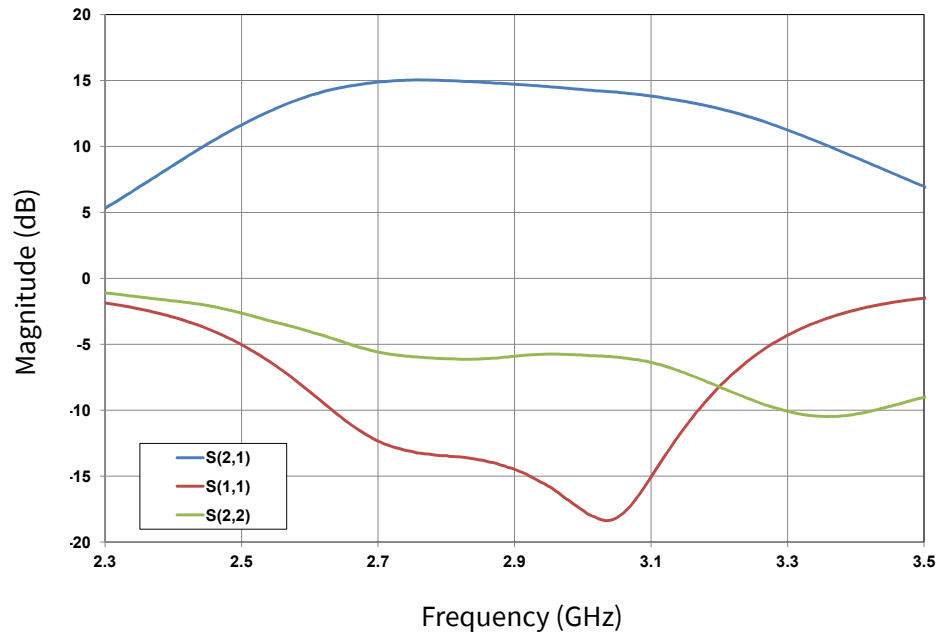
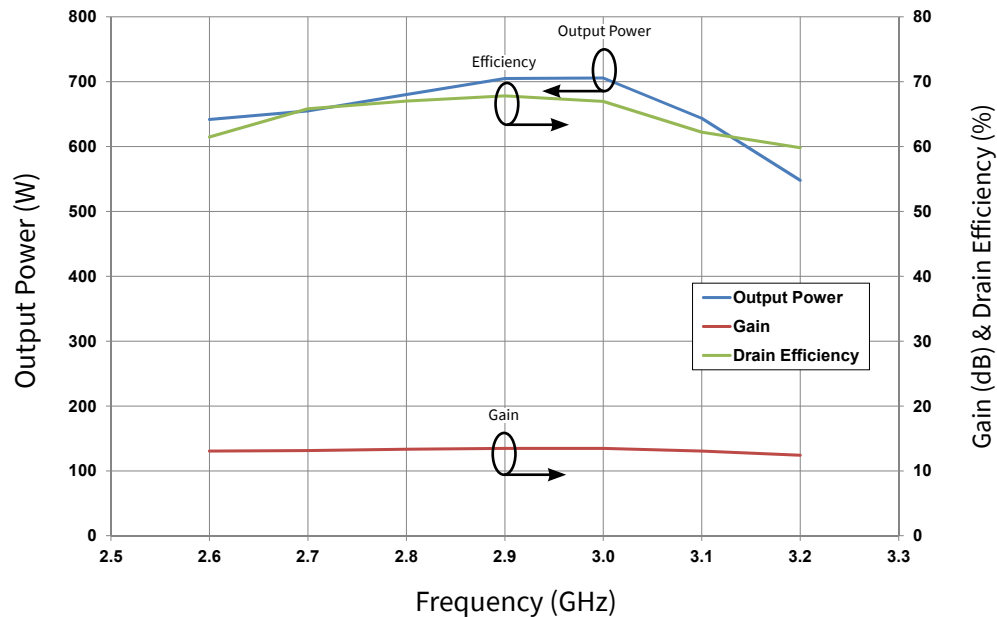
 $V_{DD} = 50\text{ V}$, $I_{DQ} = 0.5\text{ A}$ 

Figure 2. CGHV31500F Output Power and Drain Efficiency vs Frequency

 $V_{DD} = 50\text{ V}$, $I_{DQ} = 0.5\text{ A}$, $P_{IN} = 46\text{ dBm}$, Pulse Width = $100\mu\text{s}$, Duty Cycle = 10%, $T_{CASE} = 25^\circ\text{C}$ 

Typical Performance

Figure 3. CGHV31500F Drain Efficiency & Gain vs. Input Power
 $V_{DD} = 50\text{ V}$, $I_{DQ} = 500\text{ mA}$, Pulse Width = 100 μs , Duty Cycle = 10%

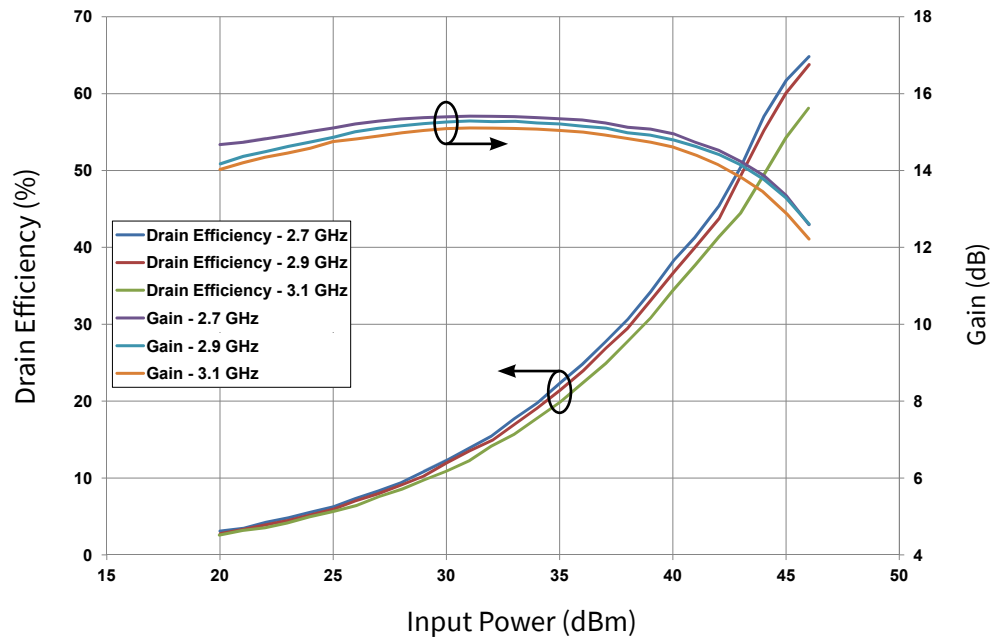
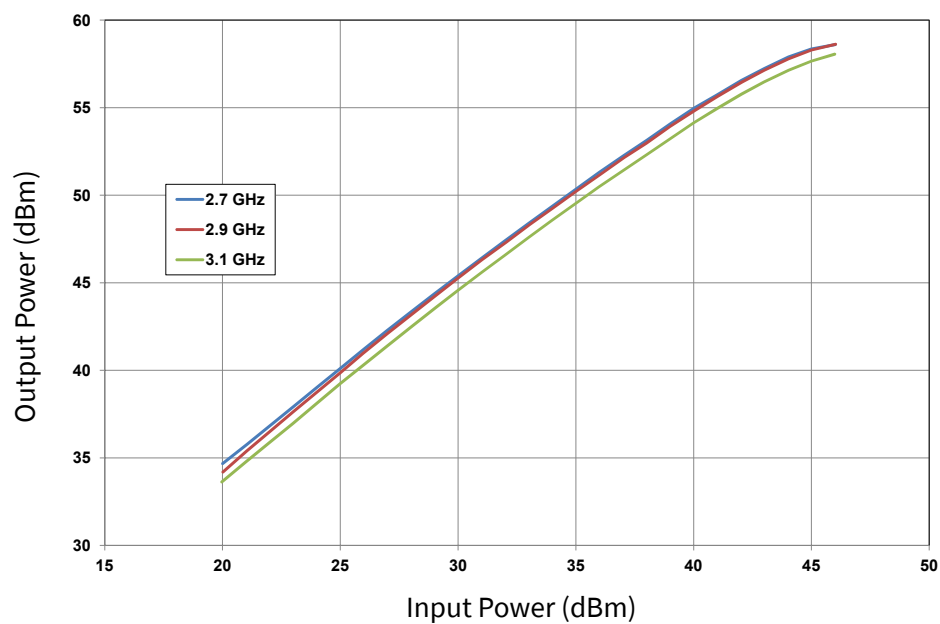


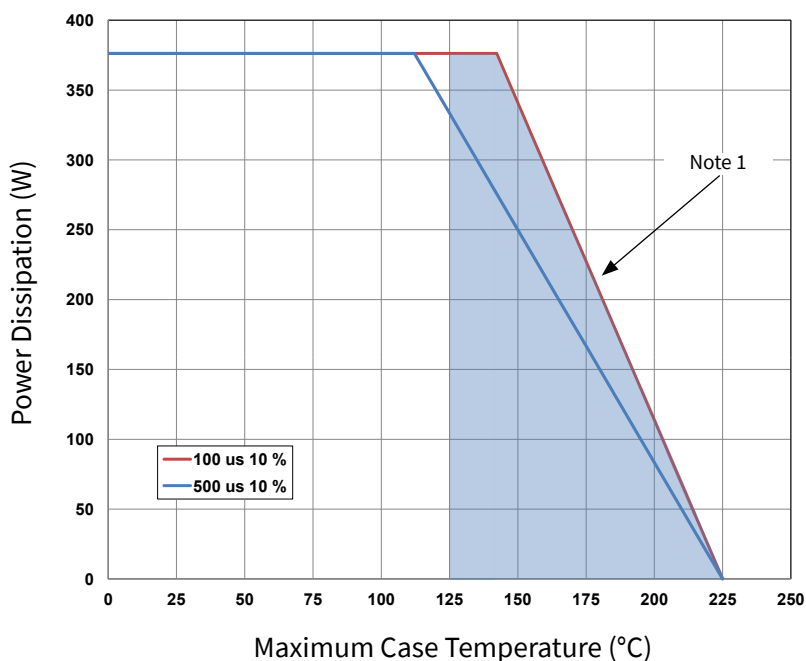
Figure 4. CGHV31500F Output Power vs. Input Power
 $V_{DD} = 50\text{ V}$, $I_{DQ} = 0.5\text{ A}$, Pulse Width = 100 μs , Duty Cycle = 10%, $T_{CASE} = 25^\circ\text{C}$



CGHV31500F-AMP Application Circuit Bill of Materials

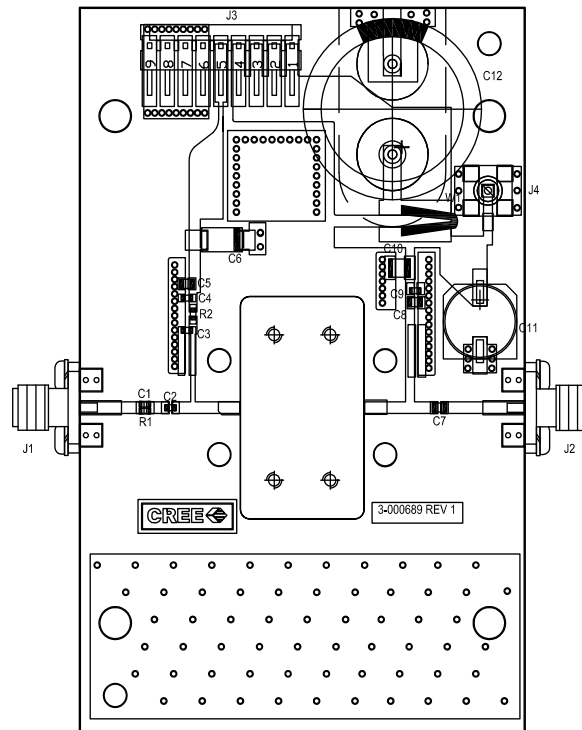
Designator	Description	Qty
R1	RES, 511, OHM, +/- 1%, 1/16W, 0603	1
R2	RES, 5.1, OHM, +/- 1%, 1/16W, 0603	1
C1	CAP, 6.8pF, +/-0.25%, 250V, 0603	1
C2, C7, C8	CAP, 10.0pF, +/-1%, 250V, 0805	3
C3	CAP, 10.0pF, +/-5%, 250V, 0603	1
C4, C9	CAP, 470pF, 5%, 100V, 0603, X	2
C5	CAP, 33000 pF, 0805, 100V, X7R	1
C6	CAP, 10uF 16V TANTALUM	1
C10	CAP, 1.0uF, 100V, 10%, X7R, 1210	1
C11	CAP, 33uF, 20%, G CASE	1
C12	CAP, 3300uF, +/-20%, 100V, ELECTROLYTIC	1
J1,J2	CONN, SMA, PANEL MOUNT JACK, FL	2
J3	HEADER, RT>PLZ, 0.1CEN LK 9POS	1
J4	CONNECTOR; SMB, Straight, JACK, SMD	1
W1	CABLE, 18 AWG, 4.2	1
-	PCB, RO4350, 2.5 X 4.0 X 0.030	1
Q1	CGHV31500F	1

CGHV31500F Power Dissipation De-rating Curve

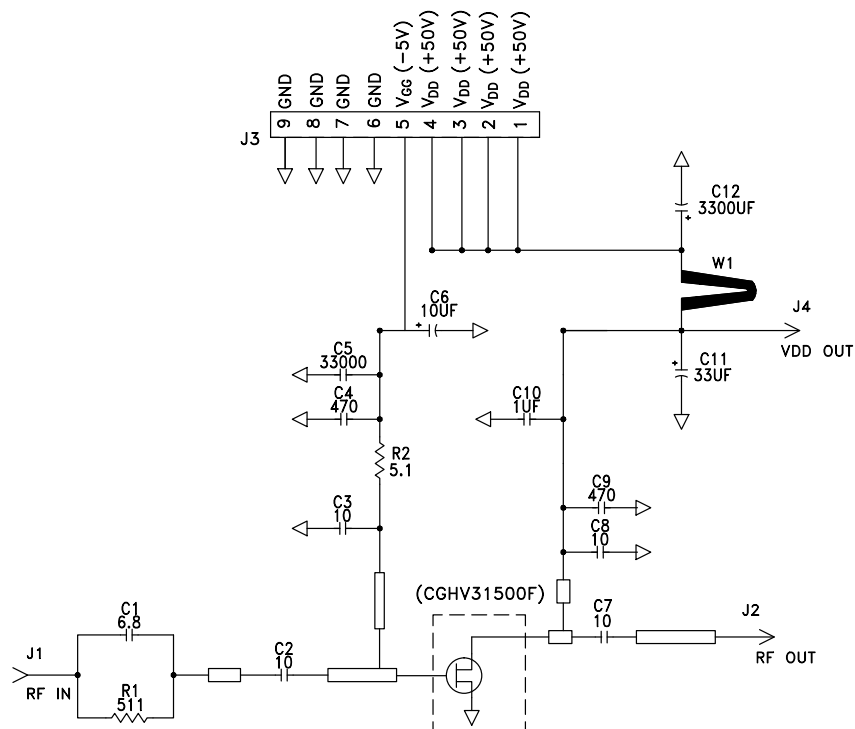


Note 1. Area exceeds Maximum Case Temperature (See Page 2).

CGHV31500F-AMP Application Circuit Outline

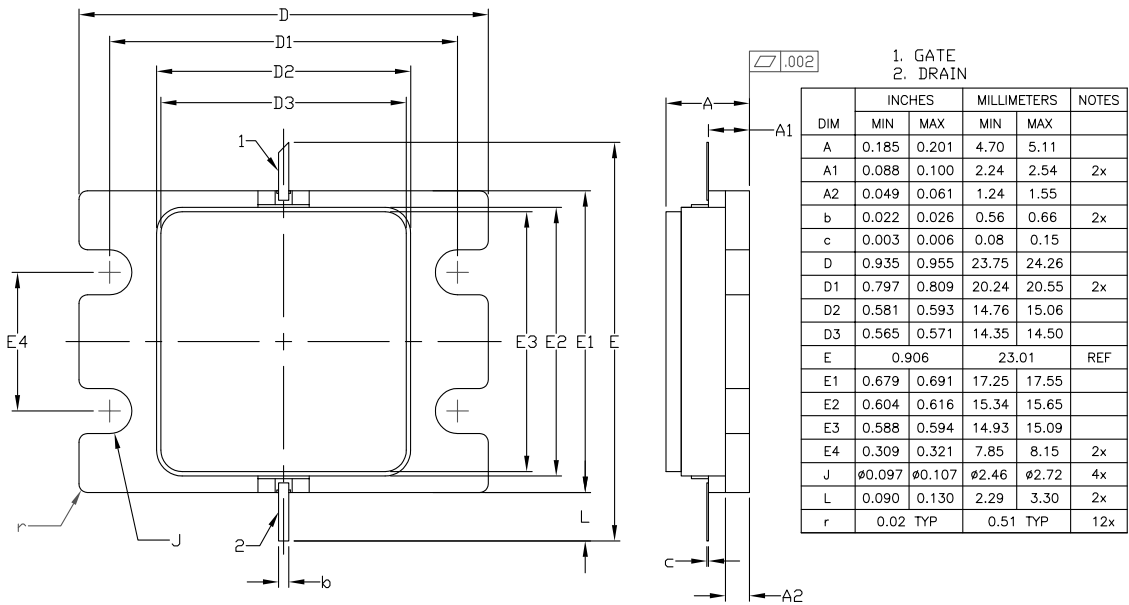


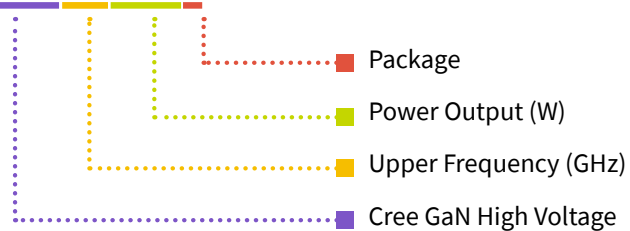
CGHV31500F-AMP Application Circuit Schematic



Product Dimensions CGHV31500F (Package Type — 440226)

- NOTES: (UNLESS OTHERWISE SPECIFIED)
- 1. INTERPRET DRAWING IN ACCORDANCE WITH ANSI Y14.5M-2009
 - 2. ADHESIVE FROM LID MAY EXTEND A MAXIMUM OF .020 BEYOND EDGE OF LID
 - 3. LID MAY BE MISALIGNED TO THE BODY OF PACKAGE BY A MAXIMUM OF .008 IN ANY DIRECTION
 - 4. ALL PLATED SURFACES ARE GOLD OVER NICKEL



Part Number System**CGHV31500F****Table 1.**

Parameter	Value	Units
Upper Frequency ¹	3.1	GHz
Power Output	500	W
Package	Flange	-

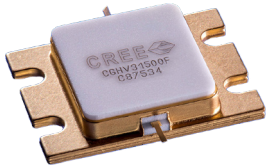
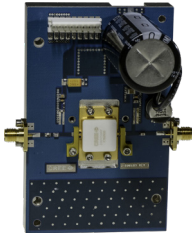
Note¹: Alpha characters used in frequency code indicate a value greater than 9.9 GHz. See Table 2 for value.

Table 2.

Character Code	Code Value
A	0
B	1
C	2
D	3
E	4
F	5
G	6
H	7
J	8
K	9
Examples:	1A = 10.0 GHz 2H = 27.0 GHz



Product Ordering Information

Order Number	Description	Unit of Measure	Image
CGHV31500F	GaN HEMT	Each	
CGHV31500F-AMP	Test board with GaN HEMT installed	Each	

For more information, please contact:

4600 Silicon Drive
Durham, North Carolina, USA 27703
www.wolfspeed.com/RF

Sales Contact
RFSales@cree.com

Notes

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